Medium-High Voltage Multilayer Ceramic Capacitor for Telecommunications Infrastructure and Industrial Equipment High frequency/Low loss Medium-High Voltage Multilayer Ceramic Capacitor for Telecommunications Infrastructure and Industrial Equipment Medium-High Voltage Multilayer Ceramic Capacitor for Medical Devices classified as GHTF Class C (Japan Class III) High frequency/Low loss Medium-High Voltage Multilayer Ceramic Capacitor

for Medical Devices classified as GHTF Class C (Japan Class III)

RELIABILITY DATA

1. Operating Temp	erature Range
Specified Value	Temperature Compensating (High Frequency type) CG(C0G) : -55 to $+125^{\circ}$ C
Specified Value	High permittivity X7R, X7S : -55 to $+125^{\circ}$ C

2. Storage Te	mperature Range
Specified Valu	Temperature Compensating (High Frequency type) CG(C0G) : -55 to +125°C
	High permittivity X7R, X7S : −55 to +125°C

3. Rated Voltage	
Specified Value 100VDC(C	(Code:H), 250VDC(Code:Q), 630VDC(Code:S)

4. Withstanding Vol	tage(Between terminals)	
Specified Value	No breakdown or damage	
Test Methods and Remarks	Applied voltage Duration Carge/discharge current	: Rated voltage(H) × 2.5, Rated voltage(Q) × 2, Rated voltage(S) × 1.2 : 1 to 5sec. : 50mA max.

5. Insulation Resist	ance	
Specified Value	Temperature Compensating 10000M Ω min	(High Frequency type)
	High permittivity 100M $\Omega~\mu$ F or 10G Ω , which	never is smaller.
Test Methods and Remarks	Applied voltage Duration Charge/discharge current	: Rated voltage(H, Q), 500V(S) : 60±5sec. : 50mA max.

6. Capacitance (Tolerance)	
Specified Value	Temperature Compensat $C < 0.5pF(\pm 0.05pF \text{ or } \pm 0.5pF \leq C < 5pF(\pm 0.1pF)$ $5pF \leq C < 10(\pm 0.25pF \text{ or } C \geq 10pF(\pm 5\%)$ (C:N High permittivity $\pm 10\%$, $\pm 20\%$	or ±0.25pF) +±0.5pF)
Test Methods and Remarks	Measuring frequency	ng (High Frequency type) : 1MHz±10% : 0.5 to 5Vrms : None : 1kHz±10% : 1±0.2Vrms : None

7. Q or Dissipation	n Factor		
	Temperature Compensating (High Frequency type) C<30pF : Q≧800+20C		
Specified Value	C≧30pF:Q≧1400	(C: Normal Capacitance)	
	High permittivity		
	3.5%max(H)		
	2.5%max(Q, S)		
	Temperature Compensa	ating (High Frequency type)	
	Measuring frequency	:1MHz±10%	
	Measuring voltage	: 0.5 to 5Vrms	
Test Methods	Bas application	: None	
and Remarks	High permittivity		
	Measuring frequency	: 1kHz±10%	
	Measuring voltage	: 1±0.2Vrms	
	Bas application	: None	

	Temperature Compensating (High Frequency type)				
	$CG(COG)$: $0 \pm 30ppm(-55 \text{ to } +125^{\circ}C)$				
Specified Value	High permittivity				
	X7R $\pm 15\%(-55 \text{ to } + 125^{\circ}\text{C})$				
	X7S $\pm 22\%(-55 \text{ to } +125^{\circ}\text{C})$				
	Temperature Compensating (High Frequency type)				
	Capacitance at 25°C and 85°C shall be measured in thermal equilibrium, and the temperature characteristic shall be calculated from the				
	following equation.				
	$\frac{(C_{85}-C_{25})}{C_{25}\times\Delta\Gamma} \times 10^6 \times [\text{ppm/}^{\circ}\text{C}]$				
	$C_{25} \times \Delta T$				
	High permittivity				
	Capacitance value at each step shall be measured in thermal equilibrium, and the temperature characteristic shall be calculated from the				
Test Methods	following equation.				
and Remarks	Step Temperature				
	1 Minimum operating temperature				
	2 25°C				
	3 Maximum operating temperature				
	$\frac{(C-C_2)}{C_2} \times 100(\%)$				
	-				
	C : Capacitance value in Step 1 or Step 3				

9. Deflection	
	Temperature Compensating (High Frequency type) Appearance : No abnormality
Specified Value	Capacitance change $\pm 5\%$ or ± 0.5 pF, whichever is larger.
	High permittivity Appearance : No abnormality Capacitance change : Within±10%
Test Methods and Remarks	Warp : 1mm (Soft Termination type:3mm) Duration : 10sec. Test board : Glass epoxy-resin substrate Thickness : 1.6mm
	(Unit: mm)
	Capacitance measurement shall be conducted with the board bent.

10. Adhesive Stren	gth of Terminal El	ectrodes
Specified Value	No terminal sep	aration or its indication.
Test Methods and Remarks	Applied force Duration	: 5N : 30±5sec.(Soft Termination type: 10±1sec)

Specified Value Initial perfo	rmance shall be satisfied.	
Test Methods and Remarks Test Methods and Remarks	range : 10 to 55 blitude : 1.5 mm nethod : 10 to 55	reatment(at 150°C for 1hr) Note1 (Only High permittivity) Hz to 10 Hz for 1 min s each in X, Y, Z directions: 6 hrs in total

12. Solderability			
Specified Value	At least 95% of terminal elec	trode is covered by new solder	
		Eutectic solder	Lead-free solder
Test Methods	Solder type	H60A or H63A	Sn-3.0Ag-0.5Cu
and Remarks	Solder temperature	230±5°C	245±3°C
	Duration	4±1	sec.

13. Resistance to Soldering				
	Temperature Compensating (High Frequency type)			
	Appearance	: No abnormality		
	Capacitance change	: Within $\pm 2.5\%$ or ± 0.25 pF, whichever is larger.		
	Insulation resistance	: Initial value		
	Withstanding voltage	(between terminals) : No abnormality		
Specified Value	High permittivity			
	Appearance	: No abnormality		
	Capacitance change	: Within $\pm 15\%$ (H), $\pm 10\%$ (Q, S)		
	Dissipation factor	: Initial value		
	Insulation resistance	: Initial value		
	Withstanding voltage	(between terminals) : No abnormality		
	Preconditioning	: Thermal treatment (at 150°C for 1hr) Note1 (Only High permittivity)		
Test Methods	Solder temperature	: 270±5℃		
and Remarks	Duration	: 3±0.5sec.		
and remarks	Preheating conditions	: 80 to 100°C, 2 to 5 min. 150 to 200°C, 2 to 5min.		
	Recovery	: 24 \pm 2hrs under the standard condition Note3		



14. Temperature Cycle(Thermal Shock)						
	Temperature Compensating (High Frequency type)					
	Appearance : No abnormality					
	Capacitance change : Within $\pm 2.5\%$ or $\pm 0.25p$ F, whichever is larger.					
	Insulation resistance : Initial value					
	Withstanding voltage (between terminals) : No abnormality					
Specified Value	High permittivity					
	Appearance : No abnormality					
	Capacitance change : Within $\pm 15\%(H)$, $\pm 7.5\%(Q, S)$					
	Dissipation factor : Initial value					
	Insulation resistance : Initial value					
	Withstanding voltage (between terminals) : No abnormality					
Preconditioning : Thermal treatment (at 150°C for 1hr) Note1						
	Conditions for 1 cycle					
	Step temperature (°C) Time (min.)					
Test Methods	1 Minimum operating temperature 30±3min.					
	2 Normal temperature 2 to 3min.					
and Remarks	3 Maximum operating temperature 30±3min.					
	4 Normal temperature 2 to 3min.					
	Number of cycles : 50 times					
	Recovery : 24 ± 2 hrs under the standard condition Note3					

15. Humidity (Steady state)				
	Temperature Compensating (High Frequency type)			
	Appearance	: No abnormality		
	Capacitance change	: Within $\pm 5\%$ or ± 0.5 pF, whichever is larger.		
	Insulation resistance	: 1000M Ω min		
Specified Value	High permittivity			
	Appearance	: No abnormality		
	Capacitance change	: Within \pm 15%		
	Dissipation factor	:7%max(H),5%max(Q,S).		
	Insulation resistance	: 25M Ω μ F or 1000M Ω , whichever is smaller.		
Test Methods and Remarks	Preconditioning	: Thermal treatment (at 150°C for 1hr) Note1 (Only High permittivity)		
	Temperature	: 40±2°C		
	Humidity	: 90 to 95%RH		
	Duration	: 500 + 24/-0 hrs		
	Recovery	: 24 \pm 2hrs under the standard condition Note3		

16. Humidity Loading			
	Temperature Compensating (High Frequency type)		
	Appearance	: No abnormality	
	Capacitance change	:C≦2.0pF:±0.4pF 2.0pF <c<10pf: c≧10pf:±7.5%<="" td="" ±0.75pf=""></c<10pf:>	
		(C: Nominal capacitance)	
	Insulation resistance	: 500M Ω min	
Specified Value			
	High permittivity		
	Appearance	: No abnormality	
	Capacitance change	: Within \pm 15%	
	Dissipation factor	: 7%max(H), 5%max(Q, S).	
	Insulation resistance	: 10M Ω μ F or 500M Ω , whichever is smaller.	
	Preconditioning	: Voltage treatment Note2 (Only High permittivity)	
	Temperature	: 60±2°C	
Test Methods	Humidity	: 90 to 95%RH	
and Remarks	Duration	: 500 +24/-0 hrs	
	Applied voltage	: Rated voltage	
	Charge/discharge current	: 50mA max.	
	Recovery	: 24 \pm 2hrs under the standard condition Note3	



17. High Tempera	ture Loading		
	Temperature Compensating (High Frequency type)		
	Appearance	: No abnormality	
	Capacitance change	: Within $\pm 3\%$ or ± 0.3 pF, whichever is larger.	
	Insulation resistance	:1000M Ω min	
Specified Value	High permittivity		
	Appearance	: No abnormality	
	Capacitance change	:Within±15%	
	Dissipation factor	: 7%max(H), 5%max(Q, S).	
	Insulation resistance	: 50M Ω μ F or 1000M Ω , whichever is smaller.	
	Preconditioning	: Voltage treatment Note2 (Only High permittivity)	
	Temperature	: Maximum operating temperature	
Test Methods	Duration	: 1000 + 24/-0 hrs	
and Remarks	Applied voltage	: Rated voltage×2(H, Q(High frequency / low loss type))	
		Rated voltage × 1.5(Q(Excluding High frequency / low loss type)), Rated voltage × 1.2(S)	
	Charge/discharge current	: 50mA max.	
	Recovery	: 24 \pm 2hrs under the standard condition Note3	
Note1 Thermal tre	eatment : Initial value shall be for 24±2hours.	measured after test sample is heat-treated at $150+0/-10^\circ C$ for an hour and kept at room temperature	
Note2 Voltage tre		measured after test sample is voltage-treated for an hour at both the temperature and voltage specified in and kept at room temperature for 24±2hours.	
Note3 Standard c	ondition : Temperature: 5 to 3	5° C, Relative humidity: 45 to 85 % RH, Air pressure: 86 to 106kPa	
	When there are ques	stions concerning measurement results, in order to provide correlation data, the test shall be conducted	
	under the following o	condition.	
	•	°C, Relative humidity: 60 to 70 % RH, Air pressure: 86 to 106kPa	
	Unless otherwise sp	ecified, all the tests are conducted under the "standard condition".	